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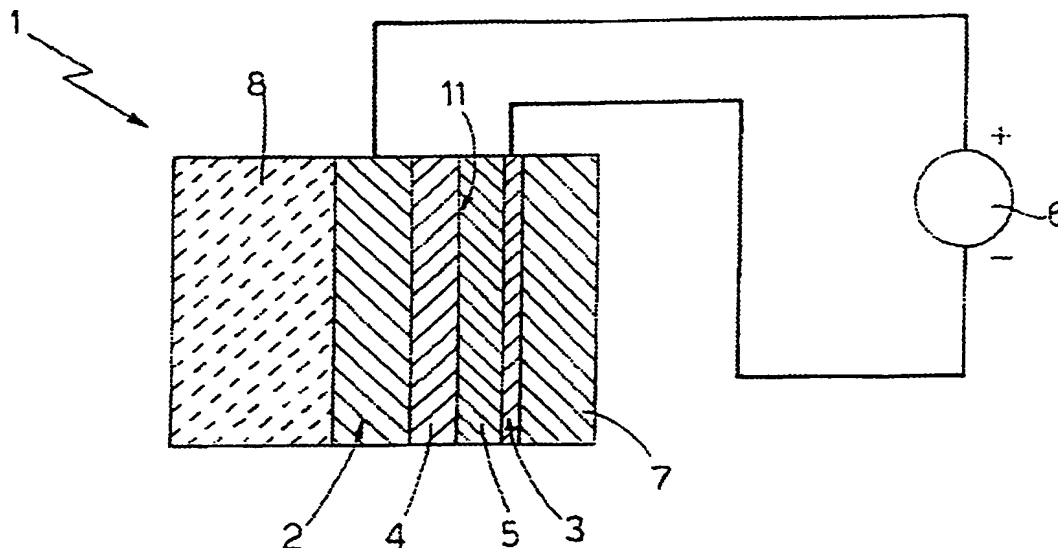
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(54) Title: METHOD FOR REDUCING THE SURFACE ROUGHNESS OF A THIN LAYER OF CONDUCTIVE OXIDES



(57) Abstract: A method for reducing the surface roughness of thin layers of conductive oxides for thin-layer opto-electronic devices envisages polishing with a finishing cloth and an abrasive compound, which has a basic pH and contains silica particles.

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*For two-letter codes and other abbreviations, refer to the "Guidance Notes on Codes and Abbreviations" appearing at the beginning of each regular issue of the PCT Gazette.*

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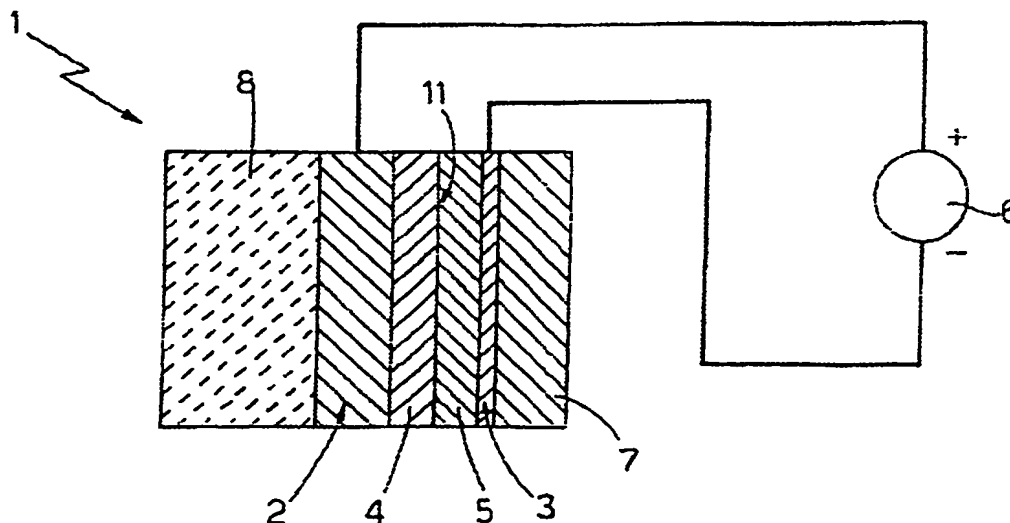
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